

**Search Notes**

Application/Control No.

10/617,297

Examiner

Minh Nguyen

Applicant(s)/Patent under  
Reexamination

OSAMURA ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search, see printout		10/7/2005	MN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPUB, USPAT, JPO, EPO, DERWENT, IBM_TDB), See printout	9/17/2004	MN
Limited search (327/419,427,478,432, 323/281-286,238,241,321-323,275, 363/49), see printout	9/17/2004	MN
Updated	5/23/2005	MN
Updated	10/7/2005	MN